

Electrical characterization and attenuation factor determination of AC-LGAD run at CNM

Thursday 22 June 2023 10:00 (20 minutes)

This presentation aims to provide an update on the recently completed AC-LGAD run at CNM. We begin by showing the electrical characterization of the produced wafers by IV and CV measurements. Several devices with different pad configurations and sizes were subjected to extensive TCT measurements. The TCT measurements reveal that the signal weakens as the laser is moved further away from the AC pad. We demonstrate the linear attenuation behavior of the signal loss between adjacent pads.

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